

# SSP1N50B

# 520V N-Channel MOSFET

## **General Description**

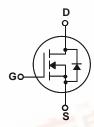
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies, power factor correction and electronic lamp ballasts based on half bridge.

#### **Features**

- 1.5A, 520V,  $R_{DS(on)} = 5.3\Omega$  @ $V_{GS} = 10 V$
- Low gate charge ( typical 8.3 nC)
- Low Crss (typical 5.5 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter	00V//0 =	SSP1N50B	Units
V <sub>DSS</sub>	Drain-Source Voltage		520	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		1.5	А
	- Continuous (T <sub>C</sub> = 100°C)		0.97	А
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	5.0	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	100	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	1.5	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	3.6	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	3.5	V/ns
$P_{D}$	Power Dissipation (T <sub>C</sub> = 25°C) - Derate above 25°C		36	W
			0.29	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

## **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		3.44	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	520			V
ΔBV <sub>DSS</sub> / ΔΤ <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$ , Referenced to 25°C		0.54		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 520 V, V <sub>GS</sub> = 0 V			10	μΑ
		V <sub>DS</sub> = 400 V, T <sub>C</sub> = 125°C			100	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$		-	-100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.75 A		4.1	5.3	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 0.75 A		1.8		S
C <sub>oss</sub> C <sub>rss</sub>	Output Capacitance Reverse Transfer Capacitance	f = 1.0 MHz		25 5.5	7.2	pF pF
Switchi	ing Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time			14	40	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 250 \text{ V}, I_D = 1.5 \text{ A},$		40	90	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 25 \Omega$		35	80	ns
t <sub>f</sub>	Turn-Off Fall Time			35	80	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = 400 V, I <sub>D</sub> = 1.5 A,		8.3	11	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		1.5		nC
Q <sub>gd</sub>	Gate-Drain Charge			3.4		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings	1		I	
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current			1	1.5	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current			-	5.0	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.5 \text{ A}$			1.4	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 1.5 \text{ A},$		230		ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI <sub>F</sub> / dt = 100 A/μs		0.94		μC

**Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 80mH, I<sub>AS</sub> = 1.5A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  1.5A, di/dt  $\leq$  200A/µs, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300µs, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

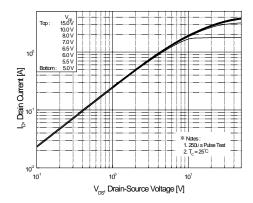


Figure 1. On-Region Characteristics

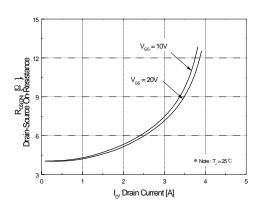


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

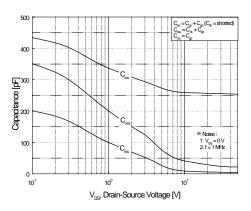


Figure 5. Capacitance Characteristics

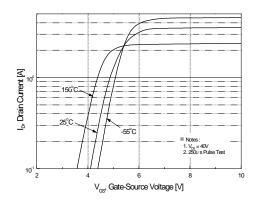


Figure 2. Transfer Characteristics

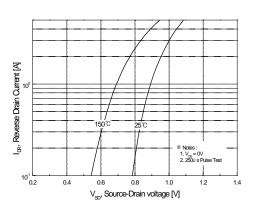


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

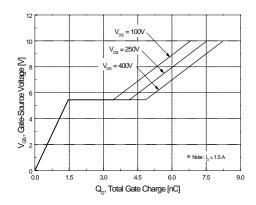


Figure 6. Gate Charge Characteristics

©2002 Fairchild Semiconductor Corporation Rev. B, May 2002

# Typical Characteristics (Continued)

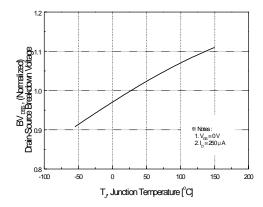


Figure 7. Breakdown Voltage Variation vs Temperature

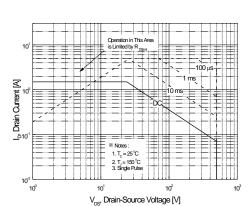


Figure 9. Maximum Safe Operating Area

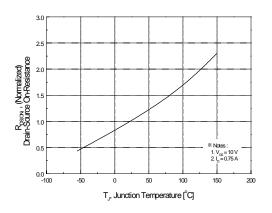


Figure 8. On-Resistance Variation vs Temperature

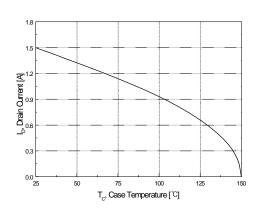


Figure 10. Maximum Drain Current vs Case Temperature

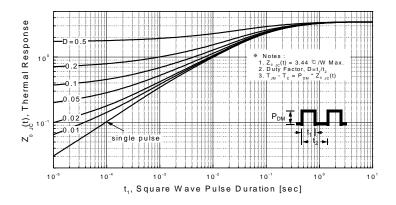
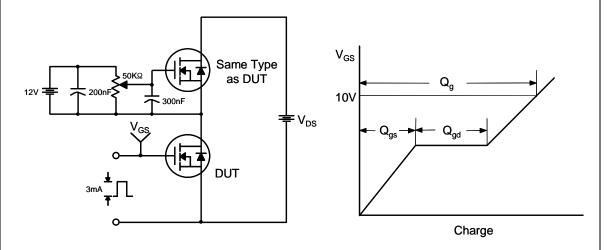


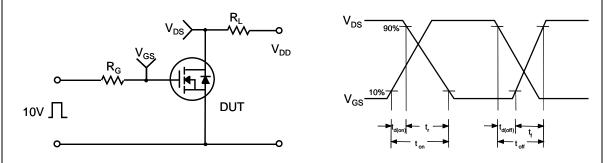
Figure 11. Transient Thermal Response Curve

©2002 Fairchild Semiconductor Corporation Rev. B, May 2002

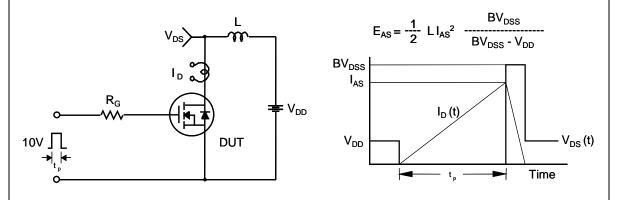
## **Gate Charge Test Circuit & Waveform**



## **Resistive Switching Test Circuit & Waveforms**



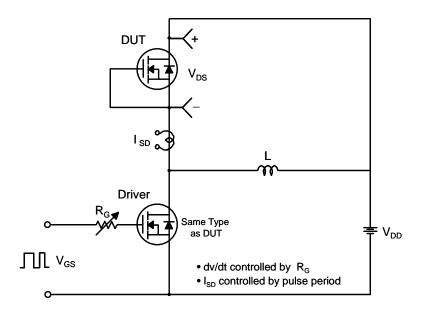
## **Unclamped Inductive Switching Test Circuit & Waveforms**

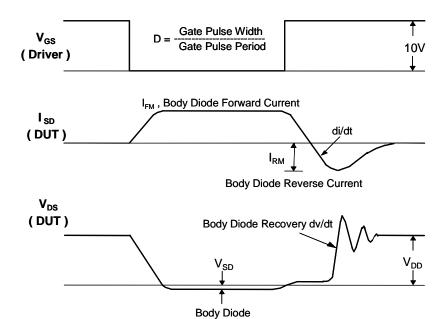


©2002 Fairchild Semiconductor Corporation

Rev. B, May 2002

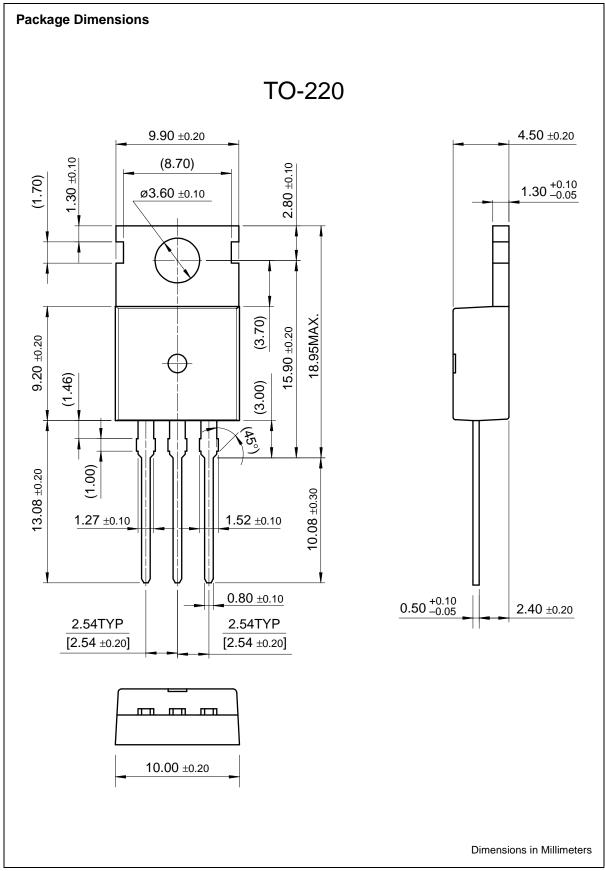
## Peak Diode Recovery dv/dt Test Circuit & Waveforms





Forward Voltage Drop

©2002 Fairchild Semiconductor Corporation



#### **TRADEMARKS**

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

$ACEx^{TM}$	FAST <sup>®</sup>	MICROWIRE™	SLIENT SWITCHER®	UHC™
Bottomless™	FASTr™	OPTOLOGIC™	SMART START™	UltraFET <sup>®</sup>
CoolFET™	FRFET™	OPTOPLANAR™	SPM™	$VCX^{TM}$
$CROSSVOLT^{TM}$	GlobalOptoisolator™	PACMAN™	STAR*POWER™	
DenseTrench™	GTO™	POP™	Stealth™	
DOME™	HiSeC™	Power247™	SuperSOT™-3	
EcoSPARK™	$I^2C^{TM}$	PowerTrench <sup>®</sup>	SuperSOT™-6	
E <sup>2</sup> CMOS™	ISOPLANAR™	QFET™	SuperSOT™-8	
EnSigna™	LittleFET™	QS™	SyncFET™	
FACT™	MicroFET™	QT Optoelectronics™	TinyLogic™	
FACT Quiet Series™	MicroPak™	Quiet Series™	TruTranslation™	

STAR\*POWER is used under license

#### **DISCLAIMER**

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS. NOR THE RIGHTS OF OTHERS.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein:

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

#### PRODUCT STATUS DEFINITIONS

#### **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

©2002 Fairchild Semiconductor Corporation